

FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

LIST OF REFERENCES CITED BY APPLICANT(S)
(Use several sheets if necessary)

Date Submitted to PTO: July 10, 2003

ATTY DOCKET NO.
2003_0615

SERIAL NO.
NEW

10/615,799

APPLICANT
Shigeru FURUMIYA et al.

FILING DATE
July 10, 2003

GROUP

2655

U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>CE</i>	AA	5,835,461	11/1998	Kobayashi et al.			
<i>NE</i>	AB	6,122,233	9/2000	Iketani et al.			
<i>CE</i>	AC	5,850,382	12/1998	Koishi et al.			
<i>CE</i>	AD	6,400,653	6/2002	Torazawa et al.			
<i>CE</i>	AE	6,160,776	12/2000	Seo			
<i>CE</i>	AF	4,825,403	4/1989	Gershenson et al.			

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO
<i>CE</i>	AG	8-315426	11/1996	JP			Abstract
	AH	11-273090	10/1999	JP			Abstract
	AI	11-288518	10/1999	JP			Abstract
	AJ	11-273090	10/1999	JP			Abstract
	AK	11-273089	10/1999	JP			Abstract
	AL	11-25492	1/1999	JP			Abstract
	AM	98/10415	3/1998	WO			
	AN	2000-235713	8/2000	JP			Abstract
	AO	2000-149271	5/2000	JP			Abstract
	AP	1 001 409	5/2000	EP			
<i>CE</i>	AQ	0 751 508	1/1997	EP			
<i>CE</i>	AR	0 930 611	7/1999	EP			

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

	AS	Muhammad Edun Primary Examiner	DATE CONSIDERED
EXAMINER			4/29/05

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Sheet 1 of 1

FORM PTO 1449 (modified)

U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICE

LIST OF REFERENCES CITED BY APPLICANT(S)
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Date Submitted to PTO: May 14, 2004

ATTY DOCKET NO.
2003-0615

SERIAL NO.
10/615,799

APPLICANT
Shigeru FURUMIYA et al.

FILING DATE
July 10, 2003

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U.S. PATENT DOCUMENTS

*EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE
<i>AG</i>	AA	6,377,537 B1	4/2002	Maeda et al.			
<i>AG</i>	AB	6,671,238 B1	12/2003	Ko et al.			
<i>AG</i>	AC	5,831,951	11/1998	Kamioka et al.			
<i>AG</i>	AD	6,259,658	7/2001	Tanoue et al.			
	AE						
	AF						
	AG						
	AH						
	AI						

FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION YES NO	
<i>AG</i>	AJ	9-282667A	10/1997	JP			Abstract	
	AK							
	AL							
	AM							
	AN							

OTHER DOCUMENT(S) (Including Author, Title, Date, Pertinent Pages, Etc.)

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	AP	
	AQ	

EXAMINER

Muhammad Edun
Primary Examiner

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Date Submitted to PTO: July 29, 2003

ATTY DOCKET NO.
2003-0615SERIAL NO.
10/615,799APPLICANT
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	AI						

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<i>CF</i>	AJ	0 177 311	04/1986	Europe				
<i>CF</i>	AK	WO 98/50914	11/1998	WIPO				
	AL							
	AM							
	AN							

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EXAMINER

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